



LIST OF REFERENCES CITED BY APPLICANT (Use several sheets if necessary)				ATTY. DOCKET NO.: 88265-7228	APPLICATION NO.: 10/661,397
				APPLICANT: Zheng et al.	GROUP: 1761
				FILING DATE: September 11, 2003	
U.S. PATENT DOCUMENTS					
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS SUBCLASS FILING DATE IF APPROPRIATE
WAW	AA	5,922,380	07/1999	Takahara	A23C 009/14
WAW	AB	5,888,562	03/1999	Hansen et al.	A23G 1/00
WAW	AC	5,364,555	11/1994	Zenner et al.	252 188.28
WAW	AD	4,897,273	01/1990	Kotaki et al.	426 118
WAW	AE	4,539,216	09/1985	Tse	426 597
WAW	AF	4,378,380	03/1983	Scarpellino et al.	A23L 1/234
WAW	AG	4,287,995	09/1981	Moriya	215 228
WAW	AH	3,540,889	11/1970	Clinton et al.	99 71
WAW	AI	3,482,987	12/1969	Pitchon et al.	426 460
FOREIGN PATENT DOCUMENTS					
		DOCUMENT NUMBER	DATE	COUNTRY	CLASS SUBCLASS TRANSLATION YES NO
WAW	AJ	EP 0861596	09/1998	EUROPE	X
WAW	AK	EP0328336	08/1989	EUROPE	X
WAW	AL	WO9518540	07/1995	PCT	X
WAW	AM	WO9611861	04/1996	PCT	X
WAW	AN	WO 03 101216	12/2003	PCT	
WAW	AO	08196212 English Abstract	08/1996	Japan	X
WAW	AP	62278948 English Abstract	12/1987	Japan	X
WAW	AQ	08-182486 English Abstract	12/1987	Japan	X
WAW	AR	640241	07/1950	Great Britain	X
WAW	AS	44914 English Abstract		Hungary	X
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.)					
WAW	AT	Holscher, W. et al., XP008007644, "Investigations of Roasted Coffee Freshness With An Improved Headspace Technique-Aromafrische Mittles Einer Vergesserten Headspace-Methodik", Forschung, vol. 195, no. 1, 1992, pages 33-38			
WAW	AU	Semmelroch, P. et al., XP000602989 "Analysis of Roasted Coffee Powders And Brews By Gas Chromatography-Olfactometry of Headspace Samples" Lebensmittel Wissenschaft Und Technologies, vol. 28, no. 3, 1995, pages 310-313			
EXAMINER Heslie Wong				DATE CONSIDERED 6/10/04 4/27/05	
*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.					

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* EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE	
LAW	AA	2,892,718	6/1959	Irwin M. Stone	99	48		
UP	AB	3,421,906	1/1-69	Ismar M. Reich et al.	99	152		
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		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							YES	NO
UP	AC	0 277 688	10/1988	EUROPE			X	
UP	AD	0 934 702	11/1999	EUROPE			X	
UP	AE	0 963 706	12/1999	EUROPE			X	
UP	AF	JP 08182486 (with English Abstract)	7/1996	JAPAN			X	
		CN 1109277 (with English Abstract)	10/1995	CHINA			X	
	AG							
UP	AH	WP00/69274	11/2000	PCT			X	
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.)								
EXAMINER					DATE CONSIDERED			
Leslie Wong					6/10/04, 4/27/05			
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	AA							
	AB							
	AC							
	AD							
	AE							
	AF							
	AG							
	AH							
FOREIGN PATENT DOCUMENTS								
		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							YES	NO
WAW	AI	1109277	04/1995	China (abstract)			X	
WAW	AJ	08-182486 English Abstract	12/1987	Japan			X	
	AK							
	AL							
	AM							
	AN							
	AO							
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